



Measuring the height of mounted substrate

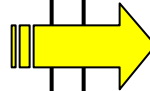
OUTLINE / PREVIOUS

Customer: Mounter manufacturer
Machinery: Mounter

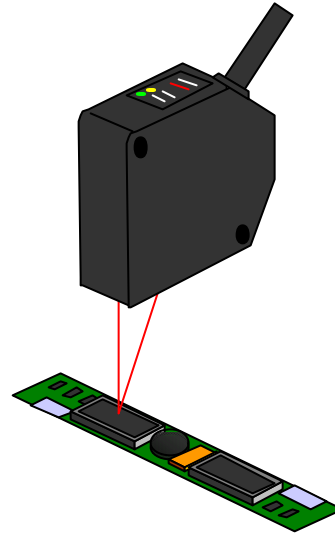
The height of a substrate is measured after components are mounted.

PROBLEM

The height of mounted substrate changes due to a variation in soldering amount or a warpage of substrate. It is required to measure the change in height without making contact.



SOLUTION



MODEL / HOW TO

HL-C203F HL-C2C

Small beam spot type **HL-C203F** is adopted.

BENEFIT 1 Highly accurate

HL-C203F is a displacement sensor with performance of sampling 100kHz, linearity $\pm 0.03\%$, resolution (*) $0.025\mu\text{m}$, the height of substrate can be accurately measured.

* **HL-C203FE** is not subject to control, whose resolution is $0.25\mu\text{m}$ (used in combination with controller **HL-C2CE**).

BENEFIT 2 Functionally-rich I/O

HL-C2C can be connected to a variety of devices such as analog output, RS-232C and USB cable, so that the stored data in these devices can be displayed and analyzed as well as the control of the sensor can be achieved.

BENEFIT 3 One sensor head can be used for either specular or diffuse reflective mode

HL-C203F can be used for either specular reflective mode or diffuse reflective mode according to the application needs.